Docket No.

217075US6YA PCT

IN RE APPLICATION OF: Joseph T. VERDEYEN et al.

SERIAL NO: 10/031,570

FILED:

March 28, 2002

FOR:

ELECTRON DENSITY MEASUREMENT AND PLASMA PROCESS CONTROL SYSTEM USING CHANGES

IN THE RESONANT FREQUENCY OF AN OPEN RESONATOR CONTAINING THE PLASMA

COMMISSIONER FOR PATENTS ALEXANDRIA, VIRGINIA 22313

SIR:

Transmitted herewith is an amendment in the above-identified application.

- No additional fee is required
- ☐ Small entity status of this application under 37 C.F.R. §1.9 and §1.27 is claimed.
- Additional documents filed herewith: Letter Submitting Drawing Replacement Sheets

Replacement Drawing Sheet (1)

The Fee has been calculated as shown below:

CLAIMS	CLAIMS REMAINING	7186	HIGHEST NUMBER PREVIOUSLY PAID	NO. EXTRA CLAIMS		RATE		CALCULATIONS
TOTAL	13	MINUS	20	0	х	\$18	=	\$0.00
INDEPENDENT	2	MINUS	3	0	х	\$86	=	\$0.00
		☐ MULTIPL	E DEPENDENT	CLAIMS	+	\$290	=	\$0.00
			TOTAL	OF ABOVE CA	LCU	JLATIC	NS	\$0.00
		☐ Reduction	by 50% for filing	by Small Entity				\$0.00
☐ Recordation of Assignment					+	\$40	=	\$0.00
:						ТОТ	AL	\$0.00

$\Box$	Α	C	heck	: in	the	amount	of	<u>\$0.00</u>	is	attacl	hed	Į.
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- ☐ Credit card payment form is attached to cover the fees in the amount of **\$0.00**
- Please charge any additional Fees for the papers being filed herewith and for which no check or credit card payment is enclosed herewith, or credit any overpayment to deposit Account No. 15-0030. A duplicate copy of this sheet is enclosed.
- If these papers are not considered timely filed by the Patent and Trademark Office, then a petition is hereby made under 37 C.F.R. §1.136, and any additional fees required under 37 C.F.R. §1.136 for any necessary extension of time may be charged to Deposit Account No. 15-0030. A duplicate copy of this sheet is enclosed.

OBLON, SPIVAK, McCLELLAND MAIER & NEUSTADT, P.C.

Steven P. Weihrouch

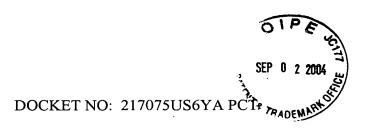
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## IN THE UNITED STATES PATENT & TRADEMARK OFFICE

IN RE APPLICATION OF

JOSEPH T. VERDEYEN ET AL. : EXAMINER: KERVEROS, JAMES C.

SERIAL NO: 10/031,570

FILED: MARCH 28, 2002 : GROUP ART UNIT: 2133

FOR: ELECTRON DENSITY MEASUREMENT AND PLASMA PROCESS CONTROL

SYSTEM USING CHANGES IN THE RESONANT FREQUENCY OF AN OPEN

RESONATOR CONTAINING THE PLASMA

## **AMENDMENT**

COMMISSIONER FOR PATENTS ALEXANDRIA, VIRGINIA 22313

SIR:

In response to the Office Action dated June 2, 2004, please amend the above-identified application as follows:

Amendments to the Claims are reflected in the listing of claims which begins on page 2 of this paper.

Amendments to the Drawings begin on page 6 of this paper and include an attached replacement sheet.

Remarks/Arguments begin on page 7 of this paper.